

Notice of Allowability

Application No.

10/035,593

Examiner

Sudhanshu C. Pathak

Applicant(s)

SIEGEL ET AL.

Art Unit

2611

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to April 7th, 2006.
2. ☒ The allowed claim(s) is/are 3-14 and re-numbered as claims 1-to12 respectively.
3. ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) ☐ All b) ☐ Some* c) ☐ None of the:
 1. ☐ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

* Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.

THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

4. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
 5. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) ☐ hereto or 2) ☐ to Paper No./Mail Date _____.
 - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.
- Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
6. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

1. ☐ Notice of References Cited (PTO-892)
2. ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/08), Paper No./Mail Date _____
4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material
5. ☐ Notice of Informal Patent Application (PTO-152)
6. ☐ Interview Summary (PTO-413), Paper No./Mail Date _____
7. ☒ Examiner's Amendment/Comment
8. ☒ Examiner's Statement of Reasons for Allowance
9. ☐ Other _____

DETAILED ACTION

1. Claims 3-to-14 are pending in the application.
2. Claims 1-2 have been canceled.

EXAMINER'S AMENDMENT

3. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it **MUST** be submitted no later than the payment of the issue fee.

The claims have been amended as follows:

- In Claim 6, line 8 **replace** "...fthat..." **with** "...that..."

Allowable Subject Matter

4. Claims 3-14 and re-numbered as claims 1-to12 respectively are allowed.
5. Claims 3-5 & 7-8 are allowable over the prior art of record because the cited references do not contain the specified limitation of a filter comprising: an analyzer that generates a low-frequency component signal and a high-frequency component signal from an input signal; a thresholding circuit that generates a processed high-frequency signal from said high-frequency component signal, said processed high-frequency signal having an amplitude of zero in those regions in which said high-frequency component signal has an amplitude that is less than a threshold value; a synthesizer that generates a filtered signal from inputs comprising said low-frequency component signal and said processed high-frequency, said filtered signal being identical to said input signal if said threshold

value is zero; and a signal converter that generates said input signal from a measured signal by performing a non-linear mathematical transformation on said measured signal; and an inverse converter that applies the inverse mathematical transformation to said filtered signal to generate an output signal.

6. Claim 6 is allowable over the prior art of record because the cited references do not contain the specified limitation of a filter comprising: an analyzer that generates a low-frequency component signal and a high-frequency component signal from an input signal; a thresholding circuit that generates a processed high-frequency signal from said high-frequency component signal, said processed high-frequency signal having an amplitude of zero in those regions in which said high-frequency component signal has an amplitude that is less than a threshold value; a synthesizer that generates a filtered signal from inputs comprising said low-frequency component signal and said processed high-frequency, said filtered signal being identical to said input signal if said threshold value is zero, wherein said threshold value depends on the amplitude of said low-frequency component signal.

7. Claims 9-14 are allowable over the prior art of record because the cited references do not contain the specified limitation of a filter comprising a first and second thresholding filters each of said first and second thresholding filters comprising: an analyzer for generating a low-frequency component signal and a high-frequency component signal from an input signal; a thresholding circuit for generating a processed high-frequency signal from said high-frequency

component signal, said processed high-frequency signal having an amplitude of zero in those regions in which said high-frequency component signal has an amplitude that is less than a threshold value; and a synthesizer for generating a filtered signal from inputs comprising said low-frequency component signal and said processed high-frequency, said filtered signal being identical to said input signal if said threshold value is zero, wherein said filtered signal generated by said first thresholding filter provides said input signal of said second thresholding, and wherein said first thresholding filter transforms said input signal thereto in a manner that is different from the manner in which said second thresholding filter transforms said input signal input thereto.

Conclusion

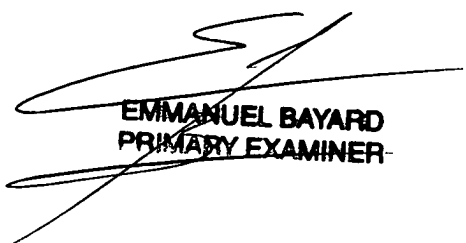
8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Sudhanshu C. Pathak whose telephone number is (571)-272-3038. The examiner can normally be reached on M-F: 9am-6pm.
- If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Chieh M. Fan can be reached on (571)-272-3042.

The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Sudhanshu C. Pathak
Examiner
Art Unit 2611



EMMANUEL BAYARD
PRIMARY EXAMINER